

ABSTRACT

The electrically programmable three-dimensional memory (EP-3DM) can be used to carry the test data and/or test-data seeds for the circuit-under-test (CUT). When integrated with the CUT, EP-3DM has minimum impact to the layout of the CUT. Apparently, CUT with integrated EP-3DM supports IC self-test. Moreover, with a large bandwidth with the CUT, EP-3DM-based IC self-test enables at-speed test.